SOUTHWEST TEST WORKSHOP

- To Advance Wafer Test Technology
- To Serve and Inform the Wafer Test Professional
- To Boldly Go Where No Workshop Has Gone Before

Long Beach, CA, June 1 to 4, 2003

WELCOME TO LONG BEACH

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WHAT IS SWTW - 2003?

- "THE" Conference for wafer test professionals
- Probe technology forum
- Not a theoretical or academic conference
- Provides practical solutions to real problems
- Mixture of vendor and user presentations
- Informal and relaxed atmosphere

SOUTHWEST TEST WORKSHOP

INFORMAL CONFERENCE

- Long breaks
- Plenty of networking opportunities
- Informal discussions
- Numerous social activities
- Meet new people & have some fun!

(Don’t tell the IEEE about the fun part)

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SOCIAL ACTIVITIES

- **Monday after dinner *light exercise***
  - **Probe Test Engineering Triathlon**
    - 1.5 Meter Cherry Seed Spitting
    - 3 Meter Paper Airplane Toss for Accuracy
    - 5 Meter Blindfolded Frisbee Throw

  - **Team Event**
    - Three (3) individuals per team
    - Must be from different companies
    - All members participate in each event

SOCIAL ACTIVITIES

Tuesday Afternoon Harbor Sightseeing Cruise

SOCIAL ACTIVITIES

- **Tuesday Evening**
- **Triathlon Awards Banquet**
- **Comedian…**

Nazareth

"American By Choice"

SOUTHWEST TEST WORKSHOP

SWTW – 2003 COMMITTEE

Organization and Technical Program

- William Mann, SWTW General Chair
- Jerry Broz, Ph.D., Point Technologies, Technical Program Chair
- Maddie Harwood, CEM Inc, Registration and Finance Chair

Technical Committee and Session Chairs

- Michael Egloff, AMD
- Tom Foerster, Jazz Semiconductor
- Gavin Gibson, Infineon Technologies
- Michael Harris, Texas Instruments
- Ken Karklin, Agilent Technologies
- Ger Koch, Philips Semiconductor
- Rey Rincon, Kulicke and Soffa
- Phil Seitzer, Agere Systems
- Roger Sinsheimer, Xandex
- Tim Swettlen, Intel
- Fred Taber, IBM Microelectronics
- Bill Williams, Motorola

TECHNICAL PROGRAM

- **Sunday, June 1, 2003**
  - Tutorial: The Impact of Design For Test on the Cost of Test
  - Keynote Speaker - Brian Matas (VP of IC Insights)

"The IC Market Recovery Outlook"

- **Monday, June 2, 2003**
  - New Probe Technologies Potpourri
  - Advances in Memory Probing
  - Vertical Probe Technologies
  - Metal Stack and Dielectric Characterization
  - Cocktail Reception & Dinner
  - Probe Test Engineering Triathlon

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TECHNICAL PROGRAM

- Tuesday, June 3, 2003
  - **MEMs Technologies**
  - **Controlling Contact Resistance**
  - **Afternoon Social Activities**
    - Long Beach Harbor Sight Seeing Cruise
  - **Cocktail Reception**
  - **Dinner and Comedy Entertainment**

- Wednesday June 4, 2003
  - **Probe Process Characterization and Improvement**
  - **Advances in Probe Card Analyzers**
  - **Best Presentation Awards**

RECOGNITION & AWARDS

- Best Overall Presentation
- Best Data Presented
- Best Presentation, Tutorial in Nature
- Most “Inspirational” Presentation
- Engineering Triathlon Winners
- Other “Special Awards”

SOUTHWEST TEST WORKSHOP

The BEST from SWTW - 2002

- **Brett Grossman and Tim Swettlen, Intel**

  "Modeling Distributed Power Delivery Effects in High Performance Sort Interface Units"

- **Sam McKnight, IBM Microelectronics**

  "Probing Lead Free Solder Bumps in Final Wafer Test"

- **William Knauer, Keithley Instruments, Inc.**

  "RF S-Parameter Measurements - A Production Solution"

- **Rainer Gaggl, Ph.D., T.I.P.S. Messtechnik GmbH**

  "Probing 10 kV and 100 Amps: Challenges and Solutions for High Voltage / High Current Wafer Probing"

http://www.swtest.org

- Central Online Repository
  - Past presentations
  - Online registration
  - With more features to come……..
- Tremendous continued success!!
  - Over eight thousand visits to the site last year
  - Thanks to “web-efforts” of Jerry Broz

Souvenirs and a "Post Card Home"

"You get to go to Long Beach and have a lot of fun……

….. and all I get is this crummy toy!"